


<b>Search Notes</b> 	<b>Application/Control No.</b> 10662917	<b>Applicant(s)/Patent Under Reexamination</b> JAMI ET AL.
	<b>Examiner</b> Ho, Huy C	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
370	437	12/18/06	HH
370	332	12/18/06	HH

SEARCH NOTES		
Search Notes	Date	Examiner
Applicant's IDS references were used in the Office Action	12/18/06	HH
EAST image and keyword search in USPATConclusion, US-PGPUB, USOCR, EPO, JPO, DERWENT, IBM_TDB (See attached search strategy)	5/8/07	HH
Search update	4/20/2009	HH
Search update	4/20/2009	HH
Search update	11/18/2009	HH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/HUY C HO/  
Examiner,Art Unit 2617